MOTOROLA
SEMICONDUCTOR
TECHNICAL DATA

1N5139 thru 1N5148 / 1N5139A thru 1N5148A

SILICON EPICAP DIODES

. . . designed for electronic tuning and harmonic-generation applications, and providing solid-state reliability to replace mechanical tuning methods.

- Guaranteed High-Frequency Q
- Guaranteed Wide Tuning Range
- Guaranteed Temperature Coefficient
- Standard 10% Capacitance Tolerance
- Complete Typical Design Curves

6.8-47 pF EPICAP VOLTAGE-VARIABLE CAPACITANCE DIODES

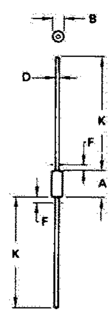
SILICON EPITAXIAL PASSIVATED

MAXIMUM RATINGS (T_C = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Reverse Voltage	V_R	60	Volts
Forward Current	I_F	250	mA
RF Power Input†	P_{in}	5	Watts
Device Dissipation @ T_A = 25°C Derate above 25°C	P_D	400 2.67	mW mW/°C
Device Dissipation @ T_C = 25°C Derate above 25°C	P_C	2.0 13.3	Watts mW/°C
Junction Temperature	T_J	+175	°C
Storage Temperature Range	T_{stg}	−65 to +200	°C

†The RF power input rating assumes that an adequate heat sink is provided.

NOTES:
1. PACKAGE CONTOUR OPTIONAL WITHIN DIA B AND LENGTH A. HEAT SLUGS, IF ANY, SHALL BE INCLUDED WITHIN THIS CYLINDER, BUT SHALL NOT BE SUBJECT TO THE MIN LIMIT OF DIA B.
2. LEAD DIA NOT CONTROLLED IN ZONES F, TO ALLOW FOR FLASH, LEAD FINISH BUILDUP, AND MINOR IRREGULARITIES OTHER THAN HEAT SLUGS.



DIM	MILLIMETERS MIN	MILLIMETERS MAX	INCHES MIN	INCHES MAX
A	5.84	7.62	0.230	0.300
B	2.16	2.72	0.085	0.107
D	0.46	0.56	0.018	0.022
F	–	1.27	–	0.050
K	25.40	38.10	1.000	1.500

All JEDEC dimensions and notes apply

CASE 51-02
DO-204AA

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ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic — All Types	Test Conditions	Symbol	Min	Typ	Max	Unit
Reverse Breakdown Voltage	I_R = 10 μAdc	BV_R	60	70	—	Vdc
Reverse Voltage Leakage Current	V_R = 55 Vdc, T_A = 25°C V_R = 55 Vdc, T_A = 150°C	I_R	— —	— —	0.02 20	μAdc
Series Inductance	f = 250 MHz, L ≈ 1/16″	L_S	—	5	—	nH
Case Capacitance	f = 1 MHz, L ≈ 1/16″	C_C	—	0.25	—	pF
Diode Capacitance Temperature Coefficient	V_R = 4 Vdc, f = 1 MHz	TC_C	—	200	300	ppm/°C

	C_T, Diode Capacitance V_R = 4 Vdc, f = 1 MHz pF			Q, Figure of Merit V_R = 4 Vdc, f = 50 MHz	α V_R = 4 Vdc, f = 1 MHz		TR, Tuning Ratio C4/C60 f = 1 MHz	
Device	**Min**	**Typ**	**Max**	**Min**	**Min**	**Typ**	**Min**	**Typ**
1N5139	6.1	6.8	7.5	350	0.37	0.40	2.7	2.9
1N5139A	6.5	6.8	7.1	350	0.37	0.40	2.7	2.9
1N5140	9.0	10.0	11.0	300	0.38	0.41	2.8	3.0
1N5140A	9.5	10.0	10.5	300	0.38	0.41	2.8	3.0
1N5141	10.8	12.0	13.2	300	0.38	0.41	2.8	3.0
1N5141A	11.4	12.0	12.6	300	0.38	0.41	2.8	3.0
1N5142	13.5	15.0	16.5	250	0.38	0.41	2.8	3.0
1N5142A	14.3	15.0	15.7	250	0.38	0.41	2.8	3.0
1N5143	16.2	18.0	19.8	250	0.38	0.41	2.8	3.0
1N5143A	17.1	18.0	18.9	250	0.38	0.41	2.8	3.0
1N5144	19.8	22.0	24.2	200	0.43	0.45	3.2	3.4
1N5144A	20.9	22.0	23.1	200	0.43	0.45	3.2	3.4
1N5145	24.3	27.0	29.7	200	0.43	0.45	3.2	3.4
1N5145A	25.7	27.0	28.3	200	0.43	0.45	3.2	3.4
1N5146	29.7	33.0	36.3	200	0.43	0.45	3.2	3.4
1N5146A	31.4	33.0	34.6	200	0.43	0.45	3.2	3.4
1N5147	36.1	39.0	42.9	200	0.43	0.45	3.2	3.4
1N5147A	37.1	39.0	40.9	200	0.43	0.45	3.2	3.4
1N5148	42.3	47.0	51.7	200	0.43	0.45	3.2	3.4
1N5148A	44.7	47.0	49.3	200	0.43	0.45	3.2	3.4

PARAMETER TEST METHODS

1. L_S, SERIES INDUCTANCE

L_S is measured on a shorted package at 250 MHz using an impedance bridge (Boonton Radio Model 250A RX Meter). L = lead length.

2. C_C, CASE CAPACITANCE

C_C is measured on an open package at 1 MHz using a capacitance bridge (Boonton Electronics Model 75A or equivalent).

3. C_T, DIODE CAPACITANCE

($C_T = C_C + C_J$). C_T is measured at 1 MHz using a capacitance bridge (Boonton Electronics Model 75A or equivalent).

4. TR, TUNING RATIO

TR is the ratio of C_T measured at 4 Vdc divided by C_T measured at 60 Vdc.

5. Q, FIGURE OF MERIT

Q is calculated by taking the G and C readings of an admittance bridge at the specified frequency and substituting in the following equations:

$$Q = \frac{2\pi fC}{G}$$

(Boonton Electronics Model 33AS8).

6. α, DIODE CAPACITANCE REVERSE VOLTAGE SLOPE

The diode capacitance, C_T (as measured at V_R = 4 Vdc, f = 1 MHz) is compared to C_T (as measured at V_R = 60 Vdc, f = 1 MHz) by the following equation which defines α.

$$\alpha = \frac{\log C_T(4) - \log C_T(60)}{\log 60 - \log 4}$$

Note that a C_T versus V_R law is assumed as shown in the following equation where C_C is included.

$$C_T = \frac{K}{V^{\alpha}}$$

7. TC_C, DIODE CAPACITANCE TEMPERATURE COEFFICIENT

TC_C is guaranteed by comparing C_T at V_R = 4 Vdc, f = 1 MHz, T_A = −65°C with C_T at V_R = 4 Vdc, f = 1 MHz, T_A = +85°C in the following equation which defines TC_C:

$$TC_C = \left| \frac{C_T(+85°C) - C_T(-65°C)}{85 + 65} \right| \cdot \frac{10^6}{C_T(25°C)}$$

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FIGURE 1 — DIODE CAPACITANCE versus REVERSE VOLTAGE

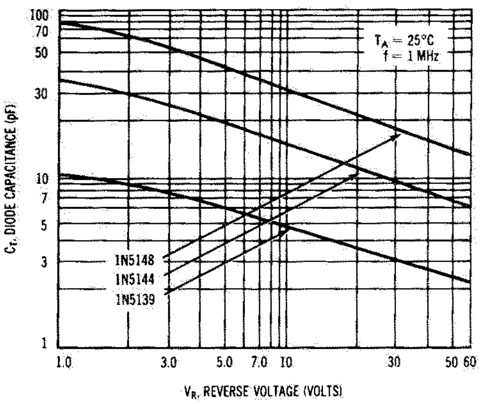


FIGURE 2 — FIGURE OF MERIT versus REVERSE VOLTAGE

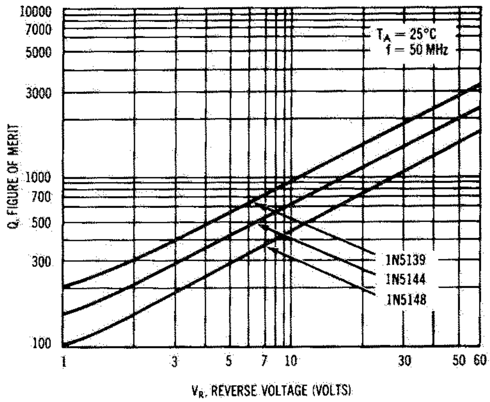


FIGURE 3 — NORMALIZED DIODE CAPACITANCE versus JUNCTION TEMPERATURE

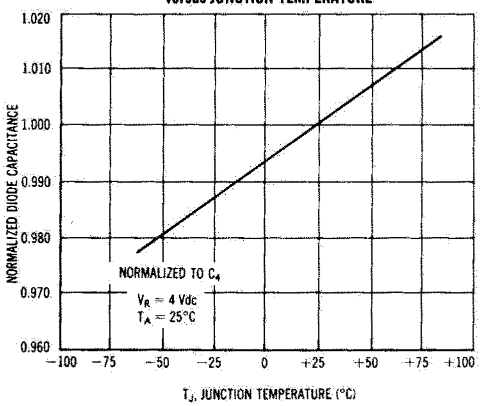


FIGURE 4 — NORMALIZED FIGURE OF MERIT versus JUNCTION TEMPERATURE

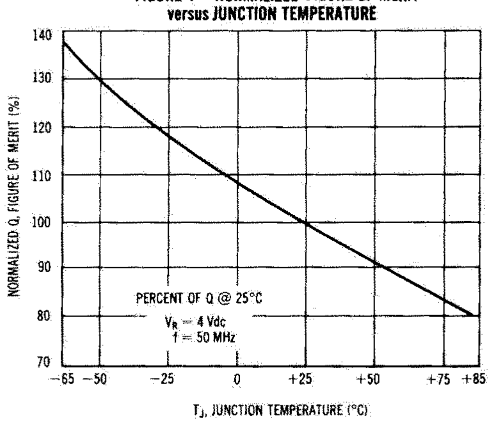


FIGURE 5 — REVERSE CURRENT versus REVERSE BIAS VOLTAGE

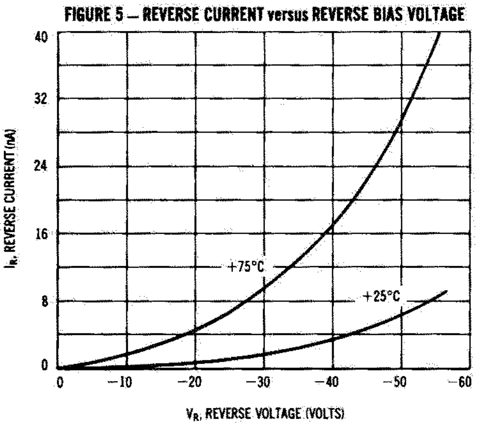
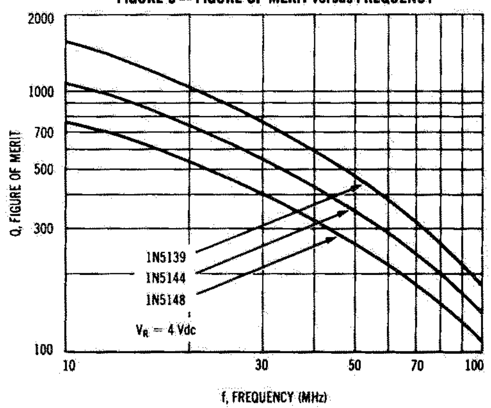


FIGURE 6 — FIGURE OF MERIT versus FREQUENCY



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